



18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

FCC ID: A3LSMJ320R4	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Reviewed by: Quality Manager
Filename: 0Y1602010270-R1.A3L	Test Dates: 02/01/2016 - 02/04/2016	EUT Type: Portable Handset	Page 47 of 49	

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Figure 18-1
Ear Reference Point HAC Phantom Alignment

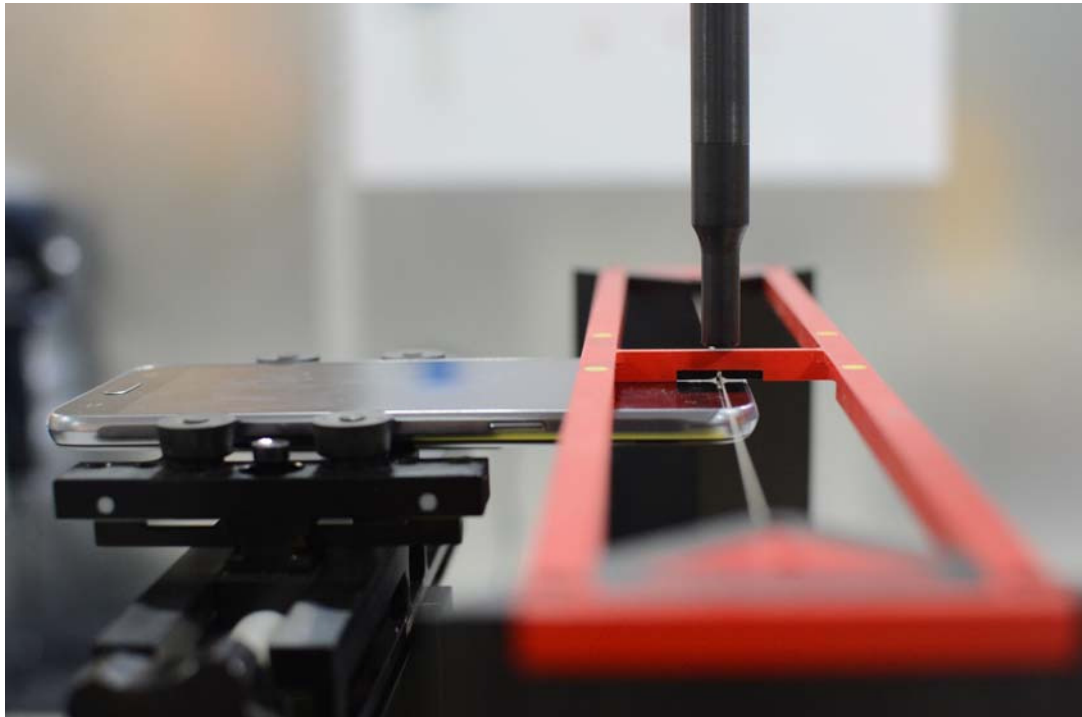




Figure 18-2
HAC Phantom Plane Alignment

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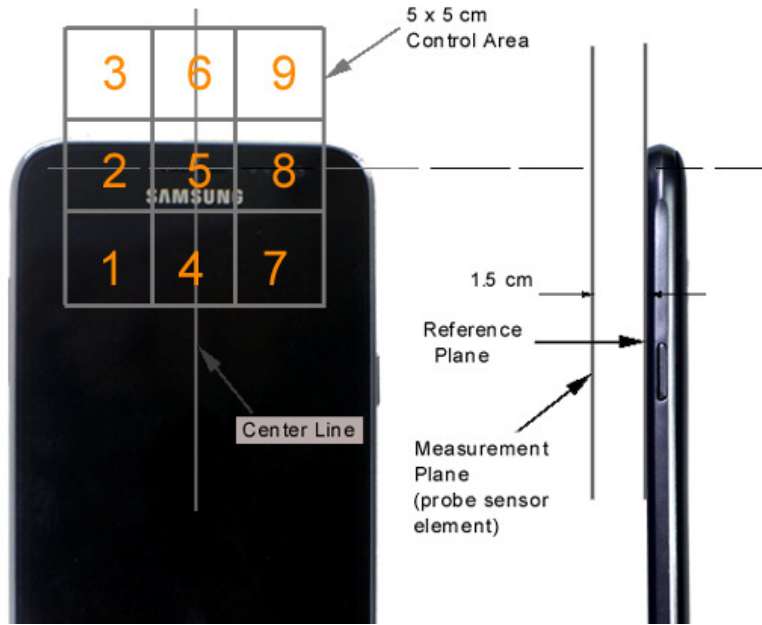




Figure 18-3 5x5 Scan grid above WD



Figure 18-4 E-Field WD Scan overlay

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